Asst. Prof. BARIŞ ARSLAN

Personal Information

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Education Information

Doctorate, University of California, San Diego, Computer Science, United States Of America 2000 - 2013
Post Graduate, University of California, San Diego, Computer Science, United States Of America 2000 - 2002
Under Graduate, Ihsan Dogramaci Bilkent University, Faculty Of Engıneerıng, Department Of Computer Engıneerıng, Turkey 1996 - 2000

Foreign Languages

English, C2 Mastery

Research Areas

Artificial Intelligence, Computer Learning and Pattern Recognition

Academic Titles / Tasks

Assistant Professor, Acibadem Mehmet Ali Aydinlar University, Faculty of Engineering, Computer Science, 2021 - Continues
Assistant Professor, Istanbul Sehir University, Faculty Of Engıneerıng And Natural Scıences, Department Of Computer Engıneerıng, 2014 - 2020

Academic and Administrative Experience

Head of Department, Istanbul Sehir University, Instıtute Of Scıence, Electrical and Computer Engineering, 2018 - 2020

Courses

Big Data Analysis, Post Graduate, 2014 - 2015, 2015 - 2016, 2016 - 2017, 2017 - 2018, 2018 - 2019, 2019 - 2020
Exploratory Data Analysis, Under Graduate, 2018 - 2019, 2019 - 2020
Machine Learning, Post Graduate, 2018 - 2019, 2019 - 2020
Machine Learning, Under Graduate, 2018 - 2019, 2019 - 2020
Computer Architecture, Under Graduate, 2014 - 2015, 2015 - 2016, 2016 - 2017, 2017 - 2018, 2018 - 2019, 2019 - 2020
Advanced Algorithms, Under Graduate, 2014 - 2015, 2015 - 2016, 2016 - 2017, 2017 - 2018
Data Visualization, Under Graduate, 2014 - 2015, 2015 - 2016, 2016 - 2017
Data Visualization, Post Graduate, 2014 - 2015, 2015 - 2016, 2016 - 2017

Articles Published in Journals That Entered SCI, SSCI and AHCI Indexes

I. **Aggressive Test Cost Reductions Through Continuous Test Effectiveness Assessment**
   Arslan B., Orailoglu A.
   IEEE TRANSACTIONS ON COMPUTER-AIDED DESIGN OF INTEGRATED CIRCUITS AND SYSTEMS, vol.35, no.12, pp.2093-2103, 2016 (Journal Indexed in SCI)
II. **Power-Aware Delay Test Quality Optimization for Multiple Frequency Domains**
   Arslan B., Orailoglu A.
   IEEE TRANSACTIONS ON COMPUTER-AIDED DESIGN OF INTEGRATED CIRCUITS AND SYSTEMS, vol.35, no.1, pp.141-154, 2016 (Journal Indexed in SCI)

Refereed Congress / Symposium Publications in Proceedings

I. **Small Delay Defect Diagnosis through Failure Observation Ordering**
   ARSLAN B.
   PROCEEDING OF 2016 IEEE INTERNATIONAL CONFERENCE ON AUTOMATION, QUALITY AND TESTING, ROBOTICS (AQTR), Cluj-Napoca, Romania, 19 - 21 May 2016, pp.67-72
II. **Tracing the Best Test Mix through Multi-Variate Quality Tracking**
   Arslan B., Orailoglu A.
   IEEE 31st VLSI Test Symposium (VTS), California, United States Of America, 29 April - 02 May 2013
III. **Full Exploitation of Process Variation Space for Continuous Delivery of Optimal Delay Test Quality**
   Arslan B., Orailoglu A.
   18th Asia and South Pacific Design Automation Conference (ASP-DAC), Yokohama, Japan, 22 - 25 January 2013, pp.552-557
IV. **Delay Test Resource Allocation and Scheduling for Multiple Frequency Domains**
   Arslan B., Orailoglu A.
   30th IEEE VLSI Test Symposium (VTS), Hawaii, United States Of America, 23 - 25 April 2012, pp.114-119
V. **Adaptive Test Framework for Achieving Target Test Quality at Minimal Cost**
   Arslan B., Orailoglu A.
   20th Asian Test Symposium (ATS), New Delhi, India, 20 - 23 November 2011, pp.323-328
VI. **Adaptive Test Optimization through Real Time Learning of Test Effectiveness**
   Arslan B., Orailoglu A.
   Design, Automation and Test in Europe Conference (DATE), Grenoble, France, 14 - 18 March 2011, pp.1430-1435
VII. **Delay Test Quality Maximization through Process-aware Selection of Test Set Size**
   Arslan B., Orailoglu A.
   IEEE International Conference on Computer Design, Amsterdam, Netherlands, 3 - 06 October 2010, pp.390-395
VIII. **Test cost reduction through a reconfigurable scan architecture**
   Arslan B., Orailoglu A.
   35th International Test Conference, Charlottetown, Canada, 26 - 28 October 2004, pp.945-952
IX. **Extending the applicability of parallel-serial scan designs**
   Arslan B., Sinanoglu O., Orailoglu A.
   IEEE International Conference on Computer Design, San-Jose, Costa Rica, 11 - 13 October 2004, pp.200-203
X. **CircularScan: A scan architecture for test cost reduction**
   Arslan B., Orailoglu A.
   Design, Automation and Test in Europe Conference and Exhibition (DATE 04), Paris, France, 16 - 20 February 2004, pp.1290-1295
XI. **Design space exploration for aggressive test cost reduction in circular scan Architectures**
   Arslan B., Orailoglu A.
   International Conference on Computer Aided Design (ICCAD 2004), San-Jose, Costa Rica, 7 - 11 November 2004, pp.726-731

XII. **Extracting precise diagnosis of bridging faults from stuck-at fault information**
Arslan B., Orailoglu A.
12th Asian Test Symposium, Xian, China, 16 - 19 November 2003, pp.230-235

XIII. **Fault dictionary size reduction through test response superposition**
Arslan B., Orailoglu A.
20th IEEE International Conference on Computer Design, Freiburg, Germany, 16 - 18 September 2002, pp.480-485

Supported Projects

Arslan B., TUBITAK Project, Gerçek Zamanlı Test Veri Analizi ile Test Optimizasyonu, 2018 - 2021

Citations

Total Citations (WOS):84
h-index (WOS):4

Non Academic Experience

Company, OakNorth, -
Company, Qualcomm Inc., QCT
Company, Marvell Semiconductor Inc., -
Company, Intel Corporation, -